

Notice of References Cited

Application/Control No.

10/026,169

Applicant(s)/Patent Under
Reexamination
PESCHKE ET AL.

Examiner

Michelle Nguyen

Art Unit

2851

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,902,030	05-1999	Blanchard, Randall D.	353/30
	C	US-5,669,686	09-1997	Moon, Seong Hak	353/98
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